



Membership Publications/Services Standards Conferences Careers/Jobs



RELEASE 1.8

Welcome
United States Patent and Trademark Office

Help FAQ Terms IEEE Peer Review

Quick Links



Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced
- CrossRef

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

IEEE Enterprise

- Access the IEEE Enterprise File Cabinet

Print Format

Your search matched 4 documents.

A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

Results Key:

JNL = Journal or Magazine CNF = Conference STD = Standard

1 A study in dynamic neural control of semiconductor fabrication processes

Card, J.P.,
Semiconductor Manufacturing, IEEE Transactions on , Volume: 13 , Issue: 3 , Aug. 2000
Pages:359 - 365

[\[Abstract\]](#) [\[PDF Full-Text \(148KB\)\]](#) IEEE JNL**2 Dynamic neural control for a plasma etch process**

Card, J.P.; Sniderman, D.L.; Klimasauskas, C.,
Neural Networks, IEEE Transactions on , Volume: 8 , Issue: 4 , July 1997
Pages:883 - 901

[\[Abstract\]](#) [\[PDF Full-Text \(404KB\)\]](#) IEEE JNL**3 SRAM bitmap shape recognition and sorting using neural networks**

Collica, R.S.; Card, J.P.; Martin, W.,
Semiconductor Manufacturing, IEEE Transactions on , Volume: 8 , Issue: 3 , Aug. 1995
Pages:326 - 332

[\[Abstract\]](#) [\[PDF Full-Text \(676KB\)\]](#) IEEE JNL**4 Advanced analysis of dynamic neural control advisories for process optimization and parts maintenance**

Card, J.P.; Chan, W.T.; Cao, A.; Martin, W.; Morgan, J.,
Advanced Semiconductor Manufacturing Conference and Workshop, 2003
IEEE/SEMI , 31 March-1 April 2003
Pages:315 - 321

[\[Abstract\]](#) [\[PDF Full-Text \(576KB\)\]](#) IEEE CNF



Membership Publications/Services Standards Conferences Careers/Jobs



RELEASE 1.8

Welcome
United States Patent and Trademark Office

...And Grow

Help FAQ Terms IEEE Peer Review

Quick Links

Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced
- CrossRef

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

IEEE Enterprise

- Access the IEEE Enterprise File Cabinet

Print Format

Your search matched **5** documents.

A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

Results Key:**JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**1 A study in dynamic neural control of semiconductor fabrication processes***Card, J.P.;*

Semiconductor Manufacturing, IEEE Transactions on , Volume: 13 , Issue: 3 , Aug. 2000

Pages:359 - 365

[\[Abstract\]](#) [\[PDF Full-Text \(148KB\)\]](#) IEEE JNL**2 Dynamic neural control for a plasma etch process***Card, J.P.; Sniderman, D.L.; Klimasauskas, C.;*

Neural Networks, IEEE Transactions on , Volume: 8 , Issue: 4 , July 1997

Pages:883 - 901

[\[Abstract\]](#) [\[PDF Full-Text \(404KB\)\]](#) IEEE JNL**3 SRAM bitmap shape recognition and sorting using neural networks***Collica, R.S.; Card, J.P.; Martin, W.;*

Semiconductor Manufacturing, IEEE Transactions on , Volume: 8 , Issue: 3 , Aug. 1995

Pages:326 - 332

[\[Abstract\]](#) [\[PDF Full-Text \(676KB\)\]](#) IEEE JNL**4 The use of unified APC/FD in the control of a metal etch area***Hyde, J.; Doxsey, J.; Card, J.;*

Advanced Semiconductor Manufacturing, 2004. ASMC '04. IEEE Conference and Workshop , 4-6 May 2004

Pages:237 - 240

[\[Abstract\]](#) [\[PDF Full-Text \(346KB\)\]](#) IEEE CNF**5 Advanced analysis of dynamic neural control advisories for process optimization and parts maintenance***Card, J.P.; Chan, W.T.; Cao, A.; Martin, W.; Morgan, J.;*

Advanced Semiconductor Manufacturing Conference and Workshop, 2003

IEEE/SEMI , 31 March-1 April 2003

Pages:315 - 321

[\[Abstract\]](#) [\[PDF Full-Text \(576KB\)\]](#) IEEE CNF

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

THIS PAGE BLANK (USPTO)



RELEASE 1.8

Welcome
United States Patent and Trademark Office

IEEE Xplore
1 Million Doc
1 Million User
...And Growing



Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced
- CrossRef

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

IEEE Enterprise

- Access the IEEE Enterprise File Cabinet

Print Format

Your search matched **191** documents.

A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

Results Key:**JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**1 On-site safety evaluation for earth fault in mining power systems**

Zeng Xiangjun; Li, K.K.; Chan, W.L.; Yin Xianggen;
Industry Applications, IEEE Transactions on , Volume: 39 , Issue: 6 , Nov.-Dec. 2003

Pages:1563 - 1569

[Abstract] [PDF Full-Text (412KB)] IEEE JNL

2 Algorithmic fusion of gene expression profiling for diffuse large B-cell lymphoma outcome prediction

Qiuming Zhu; Hongmei Cui; Kajia Cao; Chan, W.C.;
Information Technology in Biomedicine, IEEE Transactions on , Volume: 8 , Issue: 2 , June 2004
Pages:79 - 88

[Abstract] [PDF Full-Text (760KB)] IEEE JNL

3 Linearization of receivers using envelope signal injection

Chan, W.H.Y.; Bock, G.;
Microwave and Wireless Components Letters, IEEE [see also IEEE Microwave and Guided Wave Letters] , Volume: 14 , Issue: 7 , July 2004
Pages:325 - 327

[Abstract] [PDF Full-Text (160KB)] IEEE JNL

4 Linearization of mixers using predistortion and envelope signal injection

Chan, W.H.Y.; Bock, G.;
Microwave and Wireless Components Letters, IEEE [see also IEEE Microwave and Guided Wave Letters] , Volume: 14 , Issue: 3 , March 2004
Pages:100 - 102

[Abstract] [PDF Full-Text (176KB)] IEEE JNL

5 Interconnected linear multivariable systems with delays: System properties and input-output stability

Desoer, C.; Chan, W.;
Automatic Control, IEEE Transactions on , Volume: 22 , Issue: 4 , Aug 1977
Pages:604 - 610

[Abstract] [PDF Full-Text (752KB)] IEEE JNL

6 Robustness of stability conditions for linear time-invariant feedback systems

Desoer, C.; Callier, F.; Chan, W.;
Automatic Control, IEEE Transactions on , Volume: 22 , Issue: 4 , Aug 1977
Pages:586 - 590

[\[Abstract\]](#) [\[PDF Full-Text \(584KB\)\]](#) [IEEE JNL](#)

7 A basis for the controllable canonical form of linear time-invariant multiinput systems

Chan, W.; Wang, Y.;
Automatic Control, IEEE Transactions on , Volume: 23 , Issue: 4 , Aug 1978
Pages:742 - 745

[\[Abstract\]](#) [\[PDF Full-Text \(304KB\)\]](#) [IEEE JNL](#)

8 Eigenvalue assignment and stabilization of interconnected systems using local feedbacks

Chan, W.; Desoer, C.;
Automatic Control, IEEE Transactions on , Volume: 24 , Issue: 2 , Apr 1979
Pages:312 - 317

[\[Abstract\]](#) [\[PDF Full-Text \(488KB\)\]](#) [IEEE JNL](#)

9 Measurement of Nonplanar Dielectric Samples Using an Open Resonator

Chan, W.F.P.; Chambers, B.;
Microwave Theory and Techniques, IEEE Transactions on , Volume: 35 , Issue: 12 , Dec 1987
Pages:1429 - 1434

[\[Abstract\]](#) [\[PDF Full-Text \(752KB\)\]](#) [IEEE JNL](#)

10 A SFH spread spectrum synchronization algorithm for data broadcasting

Siu, Y.M.; Chan, W.S.; Leung, S.W.;
Broadcasting, IEEE Transactions on , Volume: 47 , Issue: 1 , March 2001
Pages:71 - 75

[\[Abstract\]](#) [\[PDF Full-Text \(96KB\)\]](#) [IEEE JNL](#)

11 Optimizing symbolic model checking for statecharts

Chan, W.; Anderson, R.J.; Beame, P.; Jones, D.H.; Notkin, D.; Warner, W.E.;
Software Engineering, IEEE Transactions on , Volume: 27 , Issue: 2 , Feb. 2001
Pages:170 - 190

[\[Abstract\]](#) [\[PDF Full-Text \(508KB\)\]](#) [IEEE JNL](#)

12 Rapid and accurate inter-robot position determination in robot teams

Jason Wu; Chan, W.K.; Thomas, G.;
Instrumentation and Measurement, IEEE Transactions on , Volume: 50 , Issue: 1 , Feb. 2001
Pages:163 - 168

[\[Abstract\]](#) [\[PDF Full-Text \(100KB\)\]](#) [IEEE JNL](#)

13 A novel compact PMSM with magnetic bearing for artificial heart application

Shen, J.X.; Tseng, K.J.; Vilathgamuwa, D.M.; Chan, W.K.;
Industry Applications, IEEE Transactions on , Volume: 36 , Issue: 4 , July-Aug.
2000
Pages:1061 - 1068

[\[Abstract\]](#) [\[PDF Full-Text \(612KB\)\]](#) [IEEE JNL](#)

14 Internet based transmission substation monitoring

Chan, W.L.; So, A.T.P.; Lai, L.L.;
Power Systems, IEEE Transactions on , Volume: 14 , Issue: 1 , Feb. 1999
Pages:293 - 298

[\[Abstract\]](#) [\[PDF Full-Text \(1188KB\)\]](#) [IEEE JNL](#)

15 Real-time frequency and harmonic evaluation using artificial neural networks

Lai, L.L.; Chan, W.L.; Tse, C.T.; So, A.T.P.;
Power Delivery, IEEE Transactions on , Volume: 14 , Issue: 1 , Jan. 1999
Pages:52 - 59

[\[Abstract\]](#) [\[PDF Full-Text \(660KB\)\]](#) [IEEE JNL](#)

[1](#) [2](#) [3](#) [4](#) [5](#) [6](#) [7](#) [8](#) [9](#) [10](#) [11](#) [12](#) [13](#) [Next](#)

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved



Membership Publications/Services Standards Conferences Careers/Jobs



RELEASE 1.8

Welcome
United States Patent and Trademark Office

Help FAQ Terms IEEE Peer Review

Quick Links



Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced
- CrossRef

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

IEEE Enterprise

- Access the IEEE Enterprise File Cabinet

Print Format

Your search matched 3 documents.

A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

Results Key:

JNL = Journal or Magazine CNF = Conference STD = Standard

1 Precast production scheduling with genetic algorithms

Chan, W.T.; Hu, H.;
 Evolutionary Computation, 2000. Proceedings of the 2000 Congress on , Volume: 2 , 16-19 July 2000
 Pages:1087 - 1094 vol.2

[Abstract] [PDF Full-Text (704KB)] IEEE CNF

2 Advanced analysis of dynamic neural control advisories for process optimization and parts maintenance

Card, J.P.; Chan, W.T.; Cao, A.; Martin, W.; Morgan, J.;
 Advanced Semiconductor Manufacturing Conference and Workshop, 2003
 IEEE/SEMI , 31 March-1 April 2003
 Pages:315 - 321

[Abstract] [PDF Full-Text (576KB)] IEEE CNF

3 Utilization of the saturation effect on a DC motor drive with a fuzzy controller

Lee, C.K.; Chan, W.T.;
 Industrial Automation and Control: Emerging Technologies, 1995., International IEEE/IAS Conference on , 22-27 May 1995
 Pages:342 - 349

[Abstract] [PDF Full-Text (468KB)] IEEE CNF

[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)

RELEASE 1.8

Welcome
United States Patent and Trademark Office

» Author Search

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)**Quick Links****Welcome to IEEE Xplore®**

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced
- CrossRef

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

IEEE Enterprise

- Access the IEEE Enterprise File Cabinet

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved



Membership Publications/Services Standards Conferences Careers/Jobs



RELEASE 1.8

Welcome
United States Patent and Trademark Office

Help FAQ Terms IEEE Peer Review

Quick Links



Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced
- CrossRef

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

IEEE Enterprise

- Access the IEEE Enterprise File Cabinet

Print Format

Your search matched **91 of 1124699** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

predicting failure

Search

 Check to search within this result set

Results Key:

JNL = Journal or Magazine CNF = Conference STD = Standard

1 Raytheon assessment of PRISM/spl reg/ as a field failure prediction tool

Smith, C.L.; Womack, J.B.;

Reliability and Maintainability, 2004 Annual Symposium - RAMS , 26-29 Jan. 2004

Pages:37 - 42

[\[Abstract\]](#) [\[PDF Full-Text \(336 KB\)\]](#) IEEE CNF**2 Predicting failure modes to improve reliability**

Reid, J.M.;

Reliability and Maintainability Symposium, 1990. Proceedings., Annual , 23-25 Jan. 1990

Pages:497 - 500

[\[Abstract\]](#) [\[PDF Full-Text \(380 KB\)\]](#) IEEE CNF**3 A discrete Bayes explanation of a failure-rate paradox**

Rodrigues, F.W.; Wechsler, S.;

Reliability, IEEE Transactions on , Volume: 42 , Issue: 1 , March 1993

Pages:132 - 133

[\[Abstract\]](#) [\[PDF Full-Text \(124 KB\)\]](#) IEEE JNL**4 Verifying a new design using Bayes' theorem**

Blodgett, J.D.; Dykes, R.A.; Dykes, A.A.;

Reliability and Maintainability Symposium, 1995. Proceedings., Annual , 16-19 Jan. 1995

Pages:200 - 206

[\[Abstract\]](#) [\[PDF Full-Text \(432 KB\)\]](#) IEEE CNF**5 Optimal selection of failure data for predicting failure counts**

Schneidewind, N.F.;

Software Reliability Engineering, 1993. Proceedings., Fourth International Symposium on , 3-6 Nov. 1993

Tay, A.A.O.; Lee, K.H.; Zhou, W.; Lim, K.M.;
Electronics Packaging Technology Conference, 2000. (EPTC 2000). Proceedings of
3rd , 5-7 Dec 2000
Pages:270 - 276

[\[Abstract\]](#) [\[PDF Full-Text \(588 KB\)\]](#) [IEEE CNF](#)

13 Use of importance sampling and related techniques to measure very high reliability software

Hecht, M.; Hecht, H.;
Aerospace Conference Proceedings, 2000 IEEE , Volume: 4 , 18-25 March 2000
Pages:533 - 546 vol.4

[\[Abstract\]](#) [\[PDF Full-Text \(1120 KB\)\]](#) [IEEE CNF](#)

14 A method to predict failure of solder joints caused by thermal shock using finite element analysis for RF power amplifier applications

Yang, M.C.; Cienkus, M.; Hajovsky, M.; Basey, T.;
Thermal and Thermomechanical Phenomena in Electronic Systems, 2000. ITHERM
2000. The Seventh Intersociety Conference on , Volume: 2 , 23-26 May 2000
Pages:169 - 173 vol. 2

[\[Abstract\]](#) [\[PDF Full-Text \(280 KB\)\]](#) [IEEE CNF](#)

15 Irradiation experiments with high-voltage power devices as a possible means to predict failure rates due to cosmic rays

Voss, P.; Maier, K.H.; Meczynski, W.; Becker, H.W.; Normand, E.; Wert, J.L.;
Oberg, D.I.; Majewski, P.P.;
Power Semiconductor Devices and IC's, 1997. ISPSD '97., 1997 IEEE International
Symposium on , 26-29 May 1997
Pages:169 - 172

[\[Abstract\]](#) [\[PDF Full-Text \(420 KB\)\]](#) [IEEE CNF](#)

[1](#) [2](#) [3](#) [4](#) [5](#) [6](#) [7](#) [Next](#)



RELEASE 1.8

Welcome
United States Patent and Trademark Office

Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced
- CrossRef

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

IEEE Enterprise

- Access the IEEE Enterprise File Cabinet

Print Format

Your search matched **91** of **1124699** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

predict failure

 Check to search within this result set

Results Key:

JNL = Journal or Magazine CNF = Conference STD = Standard

1 Raytheon assessment of PRISM/spl reg/ as a field failure prediction tool

Smith, C.L.; Womack, J.B.;

Reliability and Maintainability, 2004 Annual Symposium - RAMS , 26-29 Jan. 2004

Pages:37 - 42

[\[Abstract\]](#) [\[PDF Full-Text \(336 KB\)\]](#) [IEEE CNF](#)**2 Predicting failure modes to improve reliability**

Reid, J.M.;

Reliability and Maintainability Symposium, 1990. Proceedings., Annual , 23-25 Jan. 1990

Pages:497 - 500

[\[Abstract\]](#) [\[PDF Full-Text \(380 KB\)\]](#) [IEEE CNF](#)**3 A discrete Bayes explanation of a failure-rate paradox**

Rodrigues, F.W.; Wechsler, S.;

Reliability, IEEE Transactions on , Volume: 42 , Issue: 1 , March 1993

Pages:132 - 133

[\[Abstract\]](#) [\[PDF Full-Text \(124 KB\)\]](#) [IEEE JNL](#)**4 Verifying a new design using Bayes' theorem**

Blodgett, J.D.; Dykes, R.A.; Dykes, A.A.;

Reliability and Maintainability Symposium, 1995. Proceedings., Annual , 16-19 Jan. 1995

Pages:200 - 206

[\[Abstract\]](#) [\[PDF Full-Text \(432 KB\)\]](#) [IEEE CNF](#)**5 Optimal selection of failure data for predicting failure counts**

Schneidewind, N.F.;

Software Reliability Engineering, 1993. Proceedings., Fourth International Symposium on , 3-6 Nov. 1993

Pages:142 - 149

[\[Abstract\]](#) [\[PDF Full-Text \(412 KB\)\]](#) [IEEE CNF](#)

6 A Creep-Rupture Model for Two-Phase Eutectic Solders

Boon Wong; Helling, D.; Clark, R.;

Components, Hybrids, and Manufacturing Technology, IEEE Transactions on [see also IEEE Trans. on Components, Packaging, and Manufacturing Technology, Part A, B, C] , Volume: 11 , Issue: 3 , Sep 1988

Pages:284 - 290

[\[Abstract\]](#) [\[PDF Full-Text \(1096 KB\)\]](#) [IEEE JNL](#)

7 Vehicle health management research for legacy and future operational environments

Faas, P.; Schroeder, J.B.; Smith, G.;

Aerospace and Electronic Systems Magazine, IEEE , Volume: 17 , Issue: 4 , April 2002

Pages:10 - 16

[\[Abstract\]](#) [\[PDF Full-Text \(545 KB\)\]](#) [IEEE JNL](#)

8 Simulating package behavior under power dissipation using uniform thermal loading

Wakil, J.A.; Ho, P.S.;

Advanced Packaging, IEEE Transactions on [see also Components, Packaging and Manufacturing Technology, Part B: Advanced Packaging, IEEE Transactions on] , Volume: 24 , Issue: 1 , Feb 2001

Pages:60 - 65

[\[Abstract\]](#) [\[PDF Full-Text \(112 KB\)\]](#) [IEEE JNL](#)

9 A survey of reliability-prediction procedures for microelectronic devices

Bowles, J.B.;

Reliability, IEEE Transactions on , Volume: 41 , Issue: 1 , March 1992

Pages:2 - 12

[\[Abstract\]](#) [\[PDF Full-Text \(868 KB\)\]](#) [IEEE JNL](#)

10 Intelligent monitoring and control of semiconductor manufacturing equipment

Murdock, J.L.; Hayes-Roth, B.;

Expert, IEEE [see also IEEE Intelligent Systems] , Volume: 6 , Issue: 6 , Dec. 1991

Pages:19 - 31

[\[Abstract\]](#) [\[PDF Full-Text \(2440 KB\)\]](#) [IEEE JNL](#)

11 A prediction based design-for-reliability tool

Edson, B.; Xijin Tian;

Reliability and Maintainability, 2004 Annual Symposium - RAMS , 26-29 Jan. 2004

Pages:412 - 417

[\[Abstract\]](#) [\[PDF Full-Text \(364 KB\)\]](#) [IEEE CNF](#)

12 A methodology for predicting failure sites and failure modes in an IC package

Tay, A.A.O.; Lee, K.H.; Zhou, W.; Lim, K.M.;
Electronics Packaging Technology Conference, 2000. (EPTC 2000). Proceedings of
3rd , 5-7 Dec 2000
Pages:270 - 276

[\[Abstract\]](#) [\[PDF Full-Text \(588 KB\)\]](#) [IEEE CNF](#)

13 Use of importance sampling and related techniques to measure very high reliability software

Hecht, M.; Hecht, H.;
Aerospace Conference Proceedings, 2000 IEEE , Volume: 4 , 18-25 March 2000
Pages:533 - 546 vol.4

[\[Abstract\]](#) [\[PDF Full-Text \(1120 KB\)\]](#) [IEEE CNF](#)

14 A method to predict failure of solder joints caused by thermal shock using finite element analysis for RF power amplifier applications

Yang, M.C.; Cienkus, M.; Hajovsky, M.; Basey, T.;
Thermal and Thermomechanical Phenomena in Electronic Systems, 2000. ITHERM
2000. The Seventh Intersociety Conference on , Volume: 2 , 23-26 May 2000
Pages:169 - 173 vol. 2

[\[Abstract\]](#) [\[PDF Full-Text \(280 KB\)\]](#) [IEEE CNF](#)

15 Irradiation experiments with high-voltage power devices as a possible means to predict failure rates due to cosmic rays

Voss, P.; Maier, K.H.; Meczynski, W.; Becker, H.W.; Normand, E.; Wert, J.L.;
Oberg, D.I.; Majewski, P.P.;
Power Semiconductor Devices and IC's, 1997. ISPSD '97., 1997 IEEE International
Symposium on , 26-29 May 1997
Pages:169 - 172

[\[Abstract\]](#) [\[PDF Full-Text \(420 KB\)\]](#) [IEEE CNF](#)

[1](#) [2](#) [3](#) [4](#) [5](#) [6](#) [7](#) [Next](#)
